

PRESS RELEASE

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XE15: Powerfully Versatile Atomic Force Microscope

This newly developed large sample AFM provides researchers and operators with the ability to automatically image and measure up to nine individual samples.

The new XE15 from **Park Systems** is a powerfully versatile atomic force microscope (AFM) featuring a unique MultiSample™ scan. XE15 can easily scan larger samples of up to 200mm x 200mm, a vast improvement from the current AFM products on the market. The AFM is ideally suited for shared labs environments that handle a diverse range of samples, researchers doing multi variant experiments, and failure analysis engineers working on wafers.

XE15 is the only AFM that maximises the efficiency of product use with MultiSample™ scan, automated imaging of multiple samples in one pass. Specially designed multi-sample chuck holds up to nine individual samples allowing operators to scan the samples under identical environmental conditions, improving the accuracy and reliability of the data. After loading the stage with multiple samples, the scan process can be initiated. This makes it ideal for researchers wanting to scan larger samples or failure analysis engineers who need to place silicon wafers on the stage.

KEY FEATURES

- Convenient sample measurements
- Accurate scans with Crosstalk Elimination
- Better tip life
- Sample preservation
- True non-contact mode
- User friendly design and interface
- Versatile range of modes and options

For more information, contact Warsash Scientific on +61 2 9319 0122 or sales@warsash.com.au.

